

Chapter 10 in Miller and Childers

Consider a continuous time WSS process $\{X(t)\}_{t \in \mathbb{R}}$ with ACF $R_{XX}(\tau)$.

[DEF]

The PSD is the Fourier transform of the ACF

$$S_{XX}(f) = \int_{-\infty}^{+\infty} e^{j2\pi f \tau} R_{XX}(\tau) d\tau = (\mathcal{F} R_{XX})(f), f \in \mathbb{R}.$$

Fact

By the inversion formula it follows that

$$R_{XX}(\tau) = \int_{-\infty}^{+\infty} e^{-j2\pi f \tau} S_{XX}(f) df = (\mathcal{F}^{-1} S_{XX})(\tau).$$

Example

Recall that $X(t) = A \sin(\omega_0 t + \Theta)$ with $\omega_0 \in \mathbb{R}$ a constant and A and Θ independent random variables with Θ uniform $[0, 2\pi]$ has $R_{XX}(\tau) = \frac{1}{2} E(A^2) \cos(\omega_0 \tau)$ which gives $S_{XX}(f) = \frac{1}{2} E(A^2) (\delta(f - \omega_0/2\pi) + \delta(f + \omega_0/2\pi))$ by "the backway" method.

Example

One common ACF (it turns out) is $R_{XX}(t) = e^{-\alpha|\tau|}$ has $S_{XX}(f) = \frac{2\alpha}{\alpha^2 + 4\pi^2 f^2}$ since

$$\begin{aligned} \int_{-\infty}^{+\infty} e^{-j2\pi f \tau} e^{-\alpha|\tau|} d\tau &= \int_0^{+\infty} e^{-(\alpha + j2\pi f)\tau} d\tau + \int_{-\infty}^0 e^{-(\alpha - j2\pi f)\tau} d\tau \\ &= \left[\frac{e^{-(\alpha + j2\pi f)\tau}}{\alpha + j2\pi f} \right]_0^{+\infty} + \left[\frac{e^{-(\alpha - j2\pi f)\tau}}{\alpha - j2\pi f} \right]_{-\infty}^0 = \frac{1}{\alpha + j2\pi f} + \frac{1}{\alpha - j2\pi f} \end{aligned}$$

From this in turn one can conclude without calculation that $R_{XX}(\tau) = \frac{2\alpha}{\alpha^2 + 4\pi^2 \tau^2}$ has $S_{XX}(f) = e^{-\alpha|f|}$.

For a discrete time WSS process $\{X(n)\}_{n \in \mathbb{Z}}$ with ACF $R_{XX}(k)$ the PSD is given by

$$S_{XX}(f) = \mathcal{F}\{R_{XX}(k)\} = \sum_{k=-\infty}^{+\infty} e^{-j2\pi fk} R_{XX}(k) \text{ for } f \in [-\frac{1}{2}, \frac{1}{2}]$$

By Fourier series technique it follows that

$$R_{XX}(f) = \sum_{-1/2}^{1/2} e^{j2\pi f k} S_{XX}(f) df$$

Properties $S_{XX}(f) \geq 0$

$$S_{XX}(f) = S_{XX}(-f)$$

$S_{XX}(f)$ is real

$$E(X(t)^2) = \begin{cases} \int_{-\infty}^{+\infty} S_{XX}(f) df & \text{continuous time} \\ \sum_{k=-\infty}^{+\infty} S_{XX}(k) & \text{discrete time} \end{cases}$$

Proof

The first property is very hard to prove while the fourth is by inspection of the inversion formula.

In continuous time we further have

$$S_{XX}(-f) = \int_{-\infty}^{+\infty} e^{j2\pi f \tau} R_{XX}(\tau) d\tau = \int_{-\infty}^{+\infty} e^{-j2\pi f \tau} R_{XX}(-\tau) d\tau = S_{XX}(f)$$

$$\overline{S_{XX}(f)} = S_{XX}(-f) = S_{XX}(f) \quad *$$

DEF

The crosspectral density $S_{XY}(f)$ between two jointly WSS processes $X(t)$ and $Y(t)$ is defined as

$$S_{XY}(f) = \mathcal{F}\{R_{XY}(t)\}(f) \text{ where } R_{XY}(t) = E[X(t)Y(t+\tau)].$$

The bandwidth of a process is a certain measure of the width of the graph of $S_{XX}(f)$, for example, the width of the 3dB-zone.

There are several ways to measure bandwidth.

Note WSS $X(t)$ and $Y(t)$ are jointly WSS if $R_{XY}(t+\tau)$ does not depend on t .

Given an observation $(\tilde{x}(t))_{t \in [-t_0, t_0]}$ of a WSS process $\tilde{x}(t)$ it is natural to estimate (based on ergodicity in the autocorrelation)

$$\hat{R}_{\tilde{x}\tilde{x}}(\tau) = \begin{cases} \frac{1}{2t_0 - |\tau|} \int_{-t_0 + |\tau|/2}^{t_0 - |\tau|/2} \tilde{x}(t - \frac{\tau}{2}) \tilde{x}(t + \frac{\tau}{2}) dt & \text{for } |\tau| < 2t_0 \\ 0 & \text{for } |\tau| \geq 2t_0 \end{cases}$$

In reality it turns out that it is suitable to damp the estimate of $R_{\tilde{x}\tilde{x}}(\tau)$ for big $|\tau|$ close to $2t_0$ as they are more uncertain than others because based on fewer data so one uses $\hat{R}_{\tilde{x}\tilde{x}}^{(w)}(\tau) = w(\tau) \hat{R}_{\tilde{x}\tilde{x}}(\tau)$

where $|w(\tau)| \leq 1$ is a so called windowing function.

The most commonly used windowing function is

$$w(\tau) = \text{tri}(\frac{\tau}{2t_0}) = \begin{cases} 1 - \frac{|\tau|}{2t_0} & |\tau| < 2t_0 \\ 0 & |\tau| \geq 2t_0 \end{cases}$$

which in turn leads to the most commonly use ACF-estimate

$$\hat{R}_{\tilde{x}\tilde{x}}^{(htn)}(\tau) = \begin{cases} \frac{1}{2t_0} \int_{-t_0 + |\tau|/2}^{t_0 - |\tau|/2} \tilde{x}(t - \frac{\tau}{2}) \tilde{x}(t + \frac{\tau}{2}) dt & |\tau| < 2t_0 \\ 0 & |\tau| \geq 2t_0 \end{cases}$$

To estimate $S_{\tilde{x}\tilde{x}}(f)$ one simply uses

$$\hat{S}_{\tilde{x}\tilde{x}}^{(w)}(f) = (\mathcal{F} \hat{R}_{\tilde{x}\tilde{x}}^{(w)})(f).$$

The most commonly used PSD-estimate becomes

$$\hat{S}_{\text{XX}}^{(\text{tri})}(f) = (\mathcal{F} \hat{R}_{\text{XX}}^{(\text{tri})})(f).$$

We have the following useful result:

THM

$$\hat{S}_{\text{XX}}^{(\text{tri})}(f) = \frac{1}{2T_0} |\mathcal{X}_{+0}(f)|^2 \text{ where}$$

$$\mathcal{X}_{+0}(f) = (\mathcal{F} \mathcal{X}_{+0})(f) = \int_{-T_0}^{T_0} e^{-j2\pi ft} X(t) dt.$$

DEF

$$\frac{1}{2T_0} |\mathcal{X}_{+0}(f)|^2 \text{ is called } \underline{\text{the periodogram}} \text{ and}$$

denoted $\hat{S}_{\text{XX}}^{(\text{per})}(f)$.

Proof

$$\begin{aligned} \frac{1}{2T_0} |\mathcal{X}_{+0}(f)|^2 &= \frac{1}{2T_0} \mathbb{E} [\mathcal{X}_{+0}(t) * \mathcal{X}_{+0}(-t)](f) \\ &= \frac{1}{2T_0} \mathbb{E} \left[\int_{-\infty}^{+\infty} \mathcal{X}_{+0}(u) \mathcal{X}_{+0}(u-t) du \right](f) \\ &= \frac{1}{2T_0} \mathbb{E} \left[\int_{-T_0}^{T_0} \mathcal{X}_{+0}(u) \mathcal{X}_{+0}(u-t) du \right](f) \\ &= \frac{1}{2T_0} \mathbb{E} \left[\int_{-T_0 + \frac{1}{2}\Delta f}^{T_0 - \frac{1}{2}\Delta f} X(t - \frac{1}{2}\Delta f) X(t + \frac{1}{2}\Delta f) dt \right](f) \\ &= (\mathcal{F} \hat{R}_{\text{XX}}^{(\text{tri})})(f) = \hat{S}_{\text{XX}}^{(\text{tri})}(f) \end{aligned}$$

The above mentioned method to estimate PSD is called non-parametric because it does not assume any advance knowledge about the process at hand whatsoever.

Now let $\{e[n]\}_{n=-\infty}^{+\infty}$ be IID zero-mean with variance σ^2 (= discrete white noise) and consider the process $\{\mathcal{Y}[n]\}_{n=-\infty}^{+\infty}$ given by

$$Y[n] = \sum_{i=1}^p a_i Y[n-i] + \sum_{i=0}^q b_i e[n-i]$$

where $e[n]$ independent of earlier $Y[n]$

This process is called an ARMA(p,q)-process.

When $p=0$ it is called an MA(q)-process and when $q=1$ it is called an AR(p)-process.

Let us study the AR(1)-process

$$Y[n] = a_1 Y[n-1] + e_n$$

We will see in Ch N that Y is WSS so

$$R_{YY}(0) = E(Y[n]^2) = E((a_1 Y[n-1] + e_n)^2) = a_1^2 R_{YY}(0) + \sigma^2$$

so that $R_{YY}(0) = \frac{\sigma^2}{1-a_1^2}$. Further

$$\begin{aligned} R_{YY}(k) &= E(Y[n] Y[n+k]). && \text{for } k \geq 1 \\ &= E(Y[n](a_1 Y[n+k-1] + e_{n+k-1})) = a_1 R_{YY}(k-1) \end{aligned}$$

which is a difference equation with solution

$$R_{YY}(k) = a_1^{|k|} R_{YY}(0) = a_1^{|k|} \frac{\sigma^2}{1-a_1^2}.$$

Now we can do estimates \hat{a}_1 and $\hat{\sigma}^2$ of a_1 and σ^2 from $R_{YY}(0)$ and $R_{YY}(1)$ through

$$\hat{R}_{YY}(0) = \frac{\hat{\sigma}^2}{1-\hat{a}_1^2} \text{ and } \hat{R}_{YY}(1) = \hat{a}_1 \frac{\hat{\sigma}^2}{1-\hat{a}_1^2}$$

and then do a parametric estimate of

$$S_{XX}(\hat{F}) = \frac{\hat{\sigma}^2}{|1 - \hat{a}_1 e^{-j2\pi F}|^2} \quad \begin{array}{l} \text{see Ch 11 for} \\ \text{proof of this} \end{array}$$

with

$$\hat{S}_{XX}(\hat{F}) = \frac{\hat{\sigma}^2}{|1 - \hat{a}_1 e^{-j2\pi F}|^2} S_{XX}(F) \text{ formula}$$

DEF

White noise is a WSS (possibly Gaussian) process $X(t)$ with constant PSD $S_{XX}(f) = N_0/2$.

Going the "back way" we realize that $X(t)$ must have ACF $R_{XX}(z) = N_0/2 \delta(z)$ in both discrete and continuous time.